

# UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/725,756	11/30/2000	Hideyo Makino	199892US2	1614
75	90 06/30/2003			
OBLON SPIVAK MCCLELLAND			EXAMINER	
MAIER & NEUSTADT FOURTH FLOOR 1755 JEFFERSON DAVIS HIGHWAY ARLINGTON, VA 22202			РНАМ, Н	AI CHI
			ART UNIT	PAPER NUMBER
·			2861 DATE MAILED: 06/30/2003	16

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
•	09/725,756	MAKINO, HIDEYO			
Office Action Summary	Examiner	Art Unit			
	Hai C Pham	2861			
The MAILING DATE of this communicati Period f r Reply	ion appears on the cover sheet w	vith the correspondence address			
A SHORTENED STATUTORY PERIOD FOR THE MAILING DATE OF THIS COMMUNICATE OF THIS COMMUNICATE.  - Extensions of time may be available under the provisions of 37 after SIX (6) MONTHS from the mailing date of this communicate. If the period for reply specified above is less than thirty (30) day of the priod for reply is specified above, the maximum statutor is Failure to reply within the set or extended period for reply will, the company of th	CFR 1.136(a). In no event, however, may a stion.  ys, a reply within the statutory minimum of the y period will apply and will expire SIX (6) MO by statute, cause the application to become A	reply be timely filed irty (30) days will be considered timely. NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).			
1) Responsive to communication(s) filed of	on <u>18 April 2003</u> .				
2a)⊠ This action is FINAL. 2b)[	This action is non-final.				
3) Since this application is in condition for closed in accordance with the practice					
Disposition of Claims	P				
4) Claim(s) <u>2,6,8,22,26,28 and 41-44</u> is/ar					
4a) Of the above claim(s) is/are w	ithdrawn from consideration.				
5) Claim(s) is/are allowed.	!a ata d				
6) Claim(s) 2,6,8,22,26,28 and 41-44 is/are	e rejected.				
7) Claim(s) is/are objected to.					
8) Claim(s) are subject to restriction Application Papers	and/or election requirement.				
9) The specification is objected to by the Ex	vaminer				
10) The drawing(s) filed on is/are: a)		the Examiner			
,					
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  11) The proposed drawing correction filed on is: a) approved b) disapproved by the Examiner.					
If approved, corrected drawings are required in reply to this Office action.					
12) The oath or declaration is objected to by					
Priority under 35 U.S.C. §§ 119 and 120					
13)⊠ Acknowledgment is made of a claim for	foreign priority under 35 U.S.C	. § 119(a)-(d) or (f).			
a)⊠ All b)☐ Some * c)☐ None of:					
1. Certified copies of the priority doc	cuments have been received.				
2. Certified copies of the priority doc	cuments have been received in	Application No			
	onal Bureau (PCT Rule 17.2(a))				
* See the attached detailed Office action for	•	:			
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).					
<ul> <li>a) ☐ The translation of the foreign language</li> <li>15) ☐ Acknowledgment is made of a claim for contraction</li> </ul>					
Attachment(s)					
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-3) Information Disclosure Statement(s) (PTO-1449) Paper	948) 5) Notice of	w Summary (PTO-413) Paper No(s) Informal Patent Application (PTO-152)			
S. Patent and Trademark Office	office Action Summary	Part of Paper No. 16			

#### FINAL REJECTION

## Specification

- 1. The disclosure is objected to because of the following informalities:
  - Page 25, line 5, "6B" should read --5B--.

Appropriate correction is required. Applicant's cooperation in reviewing the specification and subsequently correcting any other typographical errors is greatly appreciated.

## Claim Rejections - 35 USC § 112

- 2. The following is a quotation of the second paragraph of 35 U.S.C. 112: The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.
- 3. Claims 6, 8, 26, 28, 42, 44 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

#### Claim 6:

The following limitation "means for collimating said laser beams emitted by said plurality semiconductor arrays" appears to be misleading in that only one collimator lens is claimed to collimate the laser beams emitted by said plurality semiconductor arrays together. Such claimed limitation is not supported by the specification (see specification, page 25, lines 2-5).

## Claim 26:

 Similarly, the following limitation "a collimator lens configured to collimate said laser beams emitted by said plurality semiconductor arrays" appears to be misleading in that only one collimator lens is claimed to collimate the laser beams emitted by said plurality semiconductor arrays together. Such claimed limitation is not supported by the specification (see specification, page 25, lines 2-5).

Claims 8, 28, 42, 44 are dependent from claims 6 and 26 above, and are therefore indefinite.

Appropriate correction is required.

# Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 2, 22, 41, and 43 are rejected under 35 U.S.C. 103(a) as being unpatentable over Sato et al. (U.S. 6,268,877 B1) in view of Nakajima et al. (U.S. 5,999,345) and Iwasa et al. (U.S. 6,144,685).

Sato et al. discloses a scanning optical device comprising a semiconductor laser array (multibeam laser source 1) including a plurality of light emitting points in a single package (the multibeam laser source 1 having a plurality of light-emitting points formed

Art Unit: 2861

on a single substrate surface), said plurality of light emitting points being formed to be positioned in linear relationship to one another so as to respectively emit laser beams simultaneously scanned over a recording substrate (photosensitive member 7), an adjusting means for adjusting a position of said plural semiconductor laser array so as to form a tilted angle (inclination angle  $\theta$ ) (Fig. 4), which is based on both the interval between the light emitting points and the dot density (recording density pitch P) in the sub-scanning direction, and a collimator lens (2) for collimating the laser beams emitted by the semiconductor laser array. Sato et al. further teaches the adjusting means rotating each of the semiconductor laser arrays around a midpoint (M) of a line connecting the centers of the light emitting points, and around the optical axis of the collimator lens (col. 4, lines 11-30).

Sato et al. teaches the semiconductor laser array having a plurality of lightemitting points but represented by only shows two light-emitting points, and thus does not explicitly disclose the semiconductor array having four light-emitting points positioned at an equidistant pitch.

However, it is well known in the printing art that higher number of light emitting points are commonly used to scan the surface of the photosensitive member as evidenced by Nakajima et al., which discloses a multiple beam scanning apparatus comprising a plurality of semiconductor laser arrays as light sources (LD1, LD2, Fig. 6), each including two or four light emitting points (Figs. 5 and 13, respectively) positioned in linear relationship to one another and having an equidistant pitch so as to respectively emit laser beams simultaneously scanned over a recording substrate

Art Unit: 2861

(photosensitive drum 407). Nakajima et al. further teaches the provision of an adjusting means for rotating each of the semiconductor laser arrays around a midpoint of a line connecting the centers of the light emitting points (around the rotational center C, Fig. 7).

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to provide a semiconductor array having more than two light-emitting points as taught by Nakajima et al. in the device of Sato et al. The motivation for doing so would have been to provide a higher speed to the printing device where a plurality of scanning lines can be formed simultaneously.

Sato et al. also does not expressly teach the claimed relationship:

$$\theta \leq \tan^{-1} \{1/(n-1)\}.$$

Regardless, Iwasa et al. discloses a multibeam recording apparatus in which the laser source array is arranged such that the laser beam spots on the surface of the recording medium are aligned (inclined line M', Fig. 7A) in the sub-scanning direction, and are inclined with respect to the main scanning direction (base line N') to form an angle  $\theta$  with the main scanning line. The disposition of the laser beam spots on the recording medium as well as the angle  $\theta$  are image of the corresponding structure of the laser source array, and result from a predetermined magnification. Table 2 (col. 11) shows the parameters of the multibeam recording apparatus in its basic configuration, where:

m = 30(m is the number of laser beam spots in the sub-scanning direction)  $\theta = \theta' = 88.1^{\circ}$ 

Art Unit: 2861

The angle formed by the line drawn perpendicular to the primary (main) scanning direction and the line drawn through respective centers of the first to the m-th laser beam spots becomes:

$$90^{\circ} - \theta' = 90^{\circ} - 88.1^{\circ} = 1.8^{\circ}$$

and the value of

$$tan^{-1} \{1/(m-1)\} = tan^{-1} \{1/(30-1)\} = 1.97^{\circ}$$

Therefore,

$$90^{\circ} - \theta' \le \tan - 1 \{1/(m-1)\}$$

which amply satisfies the claimed inequality.

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to modify the device of Sato et al. with the aforementioned teachings of Iwasa et al. for the purpose of adjusting the pitch of the scanning lines.

6. Claims 6, 8, 26, 28, 42, and 44 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nakajima (JP 9-236763) in view of Nakajima et al. (U.S. 5,999,345) and Iwasa et al.

Nakajima ('763) discloses a multibeam scanning device having a plurality of semiconductor laser arrays (10, 11) with corresponding collimator lenses (12, 13), and an adjusting means rotating each of the semiconductor laser arrays around a midpoint (M) of a line connecting the centers of the light emitting points, and around the optical axis of the collimator lens (12) (see Figs. 2 and 4).

Art Unit: 2861

However, Nakajima et al. ('763) does not explicitly disclose the semiconductor array having four light-emitting points positioned at an equidistant pitch.

Nevertheless, it is well known in the printing art that higher number of light emitting points are commonly used to scan the surface of the photosensitive member as evidenced by Nakajima et al. ('345), which discloses a multiple beam scanning apparatus comprising a plurality of semiconductor laser arrays as light sources (LD1, LD2, Fig. 6), each including two or four light emitting points (Figs. 5 and 13, respectively) positioned in linear relationship to one another and having an equidistant pitch so as to respectively emit laser beams simultaneously scanned over a recording substrate (photosensitive drum 407). Nakajima et al. ('345) further teaches the provision of an adjusting means for rotating each of the semiconductor laser arrays around a midpoint of a line connecting the centers of the light emitting points (around the rotational-center C, Fig. 7).

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to provide a semiconductor array having more than two light-emitting points as taught by Nakajima et al. ('345) in the device of Nakajima et al. ('763). The motivation for doing so would have been to provide a higher speed to the printing device where a plurality of scanning lines can be formed simultaneously.

Nakajima et al. ('763) also does not expressly teach the claimed relationship:  $\theta \le \tan^{-1} \{1/(n-1)\}.$ 

Regardless, Iwasa et al. discloses a multibeam recording apparatus in which the laser source array is arranged such that the laser beam spots on the surface of the

Art Unit: 2861

recording medium are aligned (inclined line M', Fig. 7A) in the sub-scanning direction, and are inclined with respect to the main scanning direction (base line N') to form an angle  $\theta$ ' with the main scanning line. The disposition of the laser beam spots on the recording medium as well as the angle  $\theta$ ' are image of the corresponding structure of the laser source array, and result from a predetermined magnification. Table 2 (col. 11) shows the parameters of the multibeam recording apparatus in its basic configuration, where:

m = 30 (m is the number of laser beam spots in the sub-scanning direction) 
$$\theta = \theta' = 88.1^{\circ}$$

The angle formed by the line drawn perpendicular to the primary (main) scanning direction and the line drawn through respective centers of the first to the m-th laser beam spots becomes:

$$90^{\circ} - \theta' = 90^{\circ} - 88.1^{\circ} = 1.8^{\circ}$$

and the value of

$$tan^{-1} \{1/(m-1)\} = tan^{-1} \{1/(30-1)\} = 1.97^{\circ}$$

Therefore,

$$90^{\circ} - \theta' \le \tan - 1 \{1/(m-1)\}$$

which amply satisfies the claimed inequality.

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to modify the device of Nakajima et al. ('763) with the aforementioned teachings of Iwasa et al. for the purpose of adjusting the pitch of the scanning lines.

Art Unit: 2861

## Response to Arguments

7. Applicant's arguments with respect to claims 2, 6, 8, 22, 26, 28, 41-44 have been considered but are moot in view of the new grounds of rejection presented in this Office action.

#### Conclusion :

8. Applicant's amendment, which changes the scope of each of the base claims, necessitated the new grounds of rejection presented in this Office action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Art Unit: 2861

Page 10

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hai C Pham whose telephone number is (703) 308-

1281. The examiner can normally be reached on T-F (8:30-5:30).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Benjamin R. Fuller can be reached on (703) 308-0079. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 308-7722, (703) 308-7724, (703) 308-7382, (703) 305-3431, (703) 305-3432 for regular communications and for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

HAI PHAM PRIMARY EXAMINER

Haich Phan

June 25, 2003